



12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN#20250618012.2
Adding CLARK-PR as additional wafer probe test site and TI Clark
as an additional Assembly/Test site for the Select Devices
Change Notification / Sample Request

Date: June 19, 2025

To: MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **60** days of the date of this notice. Lack of acknowledgement of this notice within 60 days constitutes acceptance and approval of this change. If samples or additional data are required, requests must be received within **60 days** of this notification.

The changes discussed within this PCN will not take effect any earlier than the proposed first ship date on Page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the change management team.

For sample requests or sample related questions, contact your local Field Sales Representative.

Sincerely,

Change Management Team
SC Business Services

20250618012.2
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, you have recently purchased these devices. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
TPS7B8150QDRVRQ1	TPS7B8150QDRVRQ1
TPS7B8250QDRVRQ1	TPS7B8250QDRVRQ1
TPS7B8133QDRVRQ1	TPS7B8133QDRVRQ1
TPS3836K33QDBVRQ1	TPS3836K33QDBVRQ1
TPS3838K33QDBVRQ1	NULL
TPS74601PQWDRBRQ1	NULL
TPS7B8233QDRVRQ1	TPS7B8233QDRVRQ1

Technical details of this Product Change follow on the next page(s).

PCN Number:	PCN# 20250618012.2		PCN Date:	June 19, 2025			
Title:	Adding CLARK-PR as additional wafer probe test site and TI Clark as an additional Assembly/Test site for the Select Devices						
Customer Contact:	Change Management Team	Dept:	Quality Services				
Proposed 1st Ship Date:	December 16, 2025	Sample requests accepted until:	August 18, 2025*				
*Sample requests received after August 18, 2025 will not be supported.							
Change Type:							
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Material		
<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Process		
<input checked="" type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input type="checkbox"/>	Wafer Fab Site		
<input type="checkbox"/>	Mechanical Specification	<input checked="" type="checkbox"/>	Test Site	<input type="checkbox"/>	Wafer Fab Material		
<input checked="" type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input type="checkbox"/>	Wafer Fab Process		
PCN Details							
Description of Change:							
Adding CLARK-PR as additional wafer probe test site and TI Clark as an additional Assembly/Test site for the Select Devices. Material differences between sites as follows.							
Group 1 (Assembly/Test site)							
		Current site	Additional site				
Assembly/Test Site		TI CDAT	TI Clark				
Mold compound		4222198	4208625				
Group 2 (Probe, Assembly/Test site)							
		Current site	Additional site				
Wafer probe Site		CD-PR	CLARK-PR				
Assembly/Test Site		TI CDAT	TI Clark				
Wire diam/type		1.0mil Cu	0.8mil Cu				
Mount compound		4224264	4207123				
Mold compound		4222198	4208625				
Group 3 (Probe only)							
		Current site	Additional site				
Wafer probe Site		CD-PR	CLARK-PR				
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ							
Qual details are provided in the Qual Data Section.							
Reason for Change:							
Supply continuity							
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):							
None							
Impact on Environmental Ratings							
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.							
RoHS		REACH		Green Status		IEC 62474	
<input checked="" type="checkbox"/>	No Change	<input checked="" type="checkbox"/>	No Change	<input checked="" type="checkbox"/>	No Change	<input checked="" type="checkbox"/>	No Change

Changes to product identification resulting from this PCN:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
TI CDAT	CDA	CHN	Chengdu
TI CLARK	QAB	PHL	Angeles City

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS
 MADE IN: Malaysia
 2DC: 2Q:
 MSL 2 / 260C / 1 YEAR SEAL DT
 MSL 1 / 235C / UNLIM 03/29/04
 OPT: 39
 ITEM: LBL: 5A (L)T0:1750
 (1P) SN74LS07NSR
 (Q) 2000 (D) 0336
 (31T) LOT: 3959047MLA
 (4W) TKY (1T) 7523483SI2
 (P)
 (2P) REV: (V) 0033317
 (20L) CSO: SHE (21L) CCO: USA
 (22L) ASO: MLA (23L) ACO: MYS

Group 1 Product Affected: TI Clark as A/T site

TPS7B8133QDRVRQ1	TPS7B8150QDRVRQ1.A	TPS7B8250QDRVRQ1
TPS7B8133QDRVRQ1.A	TPS7B8233QDRVRQ1	TPS7B8250QDRVRQ1.A
TPS7B8150QDRVRQ1	TPS7B8233QDRVRQ1.A	

Group 2 Product Affected: CLARK-PR, TI Clark as A/T site

TPS74601PQWDRBRQ1	TPS74601PQWDRBRQ1.A
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Group 3 Product Affected: CLARK-PR

TPS3836K33QDBVRQ1	TPS3838K33QDBVRQ1	TPS3838K33QDBVRQ1.B
TPS3836K33QDBVRQ1.A	TPS3838K33QDBVRQ1.A	

Group 1 Qual Report
Automotive Qualification Summary
(As per AEC-Q100 Rev. J and JEDEC Guidelines)
 Approve Date 28-March-2025

Product Attributes

Attributes	Qual Device: TPS7B8150QDRVRQ1	Qual Device: TPS7B8133QDRVRQ1	Qual Device: TPS7B8233QDRVRQ1	Qual Device: TPS7B8250QDRVRQ1	QBS Process, Product Reference: TPS7B8250QKVURQ1	QBS Package Reference: LPS912Q1.2DRVRQ1
Automotive Grade Level	Grade 1	Grade 1				
Operating Temp Range (C)	-40 to 125	-40 to 125				
Product Function	Power Management	Power Management				
Wafer Fab Supplier	RFAB	RFAB	RFAB	RFAB	RFAB	MH8
Assembly Site	CLARK-AT	CLARK-AT	CLARK-AT	CLARK-AT	TFME	CLARK-AT
Package Group	QFN	QFN	QFN	QFN	TO	QFN
Package Designator	DRV	DRV	DRV	DRV	KVU	DRV
Pin Count	6	6	6	6	5	6

QBS: Qual By Similarity, also known as Generic Data
 Qual Device TPS7B8150QDRVRQ1 is qualified at MSL2 260C
 Qual Device TPS7B8133QDRVRQ1 is qualified at MSL2 260C
 Qual Device TPS7B8233QDRVRQ1 is qualified at MSL2 260C
 Qual Device TPS7B8250QDRVRQ1 is qualified at MSL2 260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device:	Qual Device:	Qual Device:	Qual Device:	QBS Process, Product Reference:	QBS Package Reference:
								TPS7B8150QDRVRQ1	TPS7B8133QDRVRQ1	TPS7B8233QDRVRQ1	TPS7B8250QDRVRQ1	TPS7B8250QKVRQ1	LP5912Q1_2DRVRQ1
Test Group A - Accelerated Environment Stress Tests													
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL1 260C	-	-	-	-	-	-	3/0/0
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL3 260C	-	-	-	-	-	3/0/0	-
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-
ACU/HAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	3/231/0
ACU/HAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-
TC	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	3/231/0	3/231/0
TC-BP	A4	MIL-STD883 Method 2011	1	5	Post Temp Cycle Bond Pull	-	-	-	-	-	-	1/5/0	-
PTC	A5	JEDEC JESD22-A105	1	45	PTC	-40/125C	1000 Cycles	-	-	-	-	1/45/0	-
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	2/154/0	3/237/0
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	175C	500 Hours	-	-	-	-	1/77/0	-
Test Group B - Accelerated Lifetime Simulation Tests													
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	125C	1000 Hours	-	-	-	-	3/231/0	-
Test Group C - Package Assembly Integrity Tests													
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	-	-	-	3/90/0	-
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	-	-	-	3/90/0	-
SD	C3	JEDEC J-STD-002	1	15	PB-Free Solderability	>95% Lead Coverage	-	-	-	-	-	1/15/0	-
PD	C4	JEDEC JESD22-B100 and B108	3	10	Physical Dimensions	Cpk>1.67	-	1/10/0	-	-	-	3/30/0	-
Test Group D - Die Fabrication Reliability Tests													
EM	D1	JESD61	-	-	Electromigration	-	-	Completed Per Process Technology Requirements					
TDD	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	-	Completed Per Process Technology Requirements					
HCI	D3	JESD60 & 28	-	-	Hot Carrier Injection	-	-	Completed Per Process Technology Requirements					
BTI	D4	-	-	-	Bias Temperature Instability	-	-	Completed Per Process Technology Requirements					
SM	D5	-	-	-	Stress Migration	-	-	Completed Per Process Technology Requirements					
Test Group E - Electrical Verification Tests													
ESD	E2	AEC Q100-002	1	3	ESD HBM	-	2000 Volts	-	-	-	-	1/3/0	-
ESD	E3	AEC Q100-011	1	3	ESD CDM	-	500 Volts	-	-	-	-	1/3/0	-
LU	E4	AEC Q100-004	1	3	Latch-Up	Per AEC Q100-004	-	-	-	-	-	1/6/0	-
ED	E5	AEC Q100-009	3	30	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	1/30/0	-	-	-	3/90/0	-

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40C to +150C
 Grade 1 (or Q): -40C to +125C
 Grade 2 (or T): -40C to +105C
 Grade 3 (or I) : -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED
 Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU
 Room : AC/uHAST

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>
 TI Qualification ID: R-CHG-2403-029

**Group 2 Qual Report
 Automotive Qualification Summary
 (As per AEC and JEDEC Guidelines)**

Approve Date 28-March-2025

Product Attributes

Attributes	Qual Device:	QBS Process Reference:	QBS Package Reference:
	TPS74601PQWDRBRQ1	BQ79600PWRQ1	LP5912Q11DRVRQ1
Automotive Grade Level	Grade 1	Grade 1	Grade 1
Operating Temp Range (C)	-40 to 125	-40 to 125	-40 to 125
Product Function	Power Management	Power Management	Power Management
Wafer Fab Supplier	RFAB	RFAB	MHB
Assembly Site	CLARK-AT	MLA	CLARK-AT
Package Group	QFN	TSSOP	QFN
Package Designator	DRB	PW	DRV
Pin Count	8	16	6

QBS: Qual By Similarity, also known as Generic Data
 Qual Device TPS74601PQWDRBRQ1 is qualified at MSL2 260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device:	QBS Process Reference:	QBS Package Reference:
								TPS74601PQWDRBRQ1	BQ79600PWRQ1	LP5912Q11DRVRQ1
Test Group A - Accelerated Environment Stress Tests										
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL1 260C	-	-	-	3/4620
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL2 260C	-	-	3/0/0	-
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-
AC/uHAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Autoclave	121C/15psig	96 Hours	-	3/231/0	3/231/0

TC	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	-
Test Group B - Accelerated Lifetime Simulation Tests										
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	125C	1000 Hours	-	3/231/0	-
ELFR	B2	AEC Q100-008	3	800	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-
EDR	B3	AEC Q100-005	1	77	NVM Endurance, Data Retention, and Op Life	Per QSS-009-018	1 Step	-	3/231/0	-
Test Group C - Package Assembly Integrity Tests										
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	3/90/0	3/90/0
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	3/90/0	3/90/0
SD	C3	JEDEC J-STD-002	1	15	PB Solderability	>95% Lead Coverage	-	-	1/15/0	-
SD	C3	JEDEC J-STD-002	1	15	PB-Free Solderability	>95% Lead Coverage	-	-	1/15/0	-
PD	C4	JEDEC JESD22-B100 and B108	3	10	Physical Dimensions	Cpk>1.67	-	1/10/0	3/30/0	3/30/0
Test Group D - Die Fabrication Reliability Tests										
EM	D1	JESD61	-	-	Electromigration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
TDDB	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
HCI	D3	JESD60 & 28	-	-	Hot Carrier Injection	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
BTI	D4	-	-	-	Bias Temperature Instability	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
Test Group E - Electrical Verification Tests										
ED	E5	AEC Q100-009	3	30	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	2/60/0	-

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40C to +150C

Grade 1 (or Q): -40C to +125C

Grade 2 (or T): -40C to +105C

Grade 3 (or I) : -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED

Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room : AC/uHAST

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-CHG-2402-117

ZVEI IDs: SEM-PA-07, SEM-PA-08, SEM-PA-11, SEM-PA-18, SEM-TF-01

In performing change qualifications, Texas Instruments follows integrated circuit industry standards in performing defect mechanism analysis and failure mechanism-based accelerated environmental testing to ensure wafer fab process, assembly process and product quality and reliability. As encouraged by these standards, TI uses both product-specific and generic (family) data in qualifying its changes. For devices to be categorized as a 'product qualification family' for generic data purposes, they must share similar product, wafer fab process and assembly process elements. The applicability of generic data (also known at TI as Qualification by Similarity (QBS)) is determined by the Reliability Engineering function following these industry standards. Generic data is shown in the qualification report in columns titled "QBS Process" (for wafer fab process), "QBS Package" (for assembly process) and "QBS Product" (for product family).

For questions regarding this notice, e-mails can be sent to Change Management team or your local Field Sales Representative.

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